

© Copyright SEK. Reproduction in any form without permission is prohibited.

Halvledarkomponenter – Halvledargränssnitt för kommunikation genom människokroppen (HBC) – Del 2: Bestämning av gränssnittets egenskaper

*Semiconductor devices –
Semiconductor interface for human body communication –
Part 2: Characterization of interfacing performances*

Som svensk standard gäller europastandarden EN 62779-2:2016. Den svenska standarden innehåller den officiella engelska språkversionen av EN 62779-2:2016.

Nationellt förord

Europastandarden EN 62779-2:2016

består av:

- **europastandardens ikraftsättningsdokument**, utarbetat inom CENELEC
- **IEC 62779-2, First edition, 2016 - Semiconductor devices - Semiconductor interface for human body communication - Part 2: Characterization of interfacing performances**

utarbetad inom International Electrotechnical Commission, IEC.

Standarder underlättar utvecklingen och höjer elsäkerheten

Det finns många fördelar med att ha gemensamma tekniska regler för bl a mätning, säkerhet och provning och för utförande, skötsel och dokumentation av elprodukter och elanläggningar.

Genom att utforma sådana standarder blir säkerhetsfordringar tydliga och utvecklingskostnaderna rimliga samtidigt som marknadens acceptans för produkten eller tjänsten ökar.

Många standarder inom elområdet beskriver tekniska lösningar och metoder som åstadkommer den elsäkerhet som föreskrivs av svenska myndigheter och av EU.

SEK är Sveriges röst i standardiseringsarbetet inom elområdet

SEK Svensk Elstandard svarar för standardiseringen inom elområdet i Sverige och samordnar svensk medverkan i internationell och europeisk standardisering. SEK är en ideell organisation med frivilligt deltagande från svenska myndigheter, företag och organisationer som vill medverka till och påverka utformningen av tekniska regler inom elektrotekniken.

SEK samordnar svenska intressenters medverkan i SEKs tekniska kommittéer och stödjer svenska experters medverkan i internationella och europeiska projekt.

Stora delar av arbetet sker internationellt

Utformningen av standarder sker i allt väsentligt i internationellt och europeiskt samarbete. SEK är svensk nationalkommitté av International Electrotechnical Commission (IEC) och Comité Européen de Normalisation Electrotechnique (CENELEC).

Standardiseringsarbetet inom SEK är organiserat i referensgrupper bestående av ett antal tekniska kommittéer som speglar hur arbetet inom IEC och CENELEC är organiserat.

Arbetet i de tekniska kommittéerna är öppet för alla svenska organisationer, företag, institutioner, myndigheter och statliga verk. Den årliga avgiften för deltagandet och intäkter från försäljning finansierar SEKs standardiseringsverksamhet och medlemsavgift till IEC och CENELEC.

Var med och påverka!

Den som deltar i SEKs tekniska kommittéarbete har möjlighet att påverka framtida standarder och får tidig tillgång till information och dokumentation om utvecklingen inom sitt teknikområde. Arbetet och kontakterna med kollegor, kunder och konkurrenter kan gynnsamt påverka enskilda företags affärsutveckling och bidrar till deltagarnas egen kompetensutveckling.

Du som vill dra nytta av dessa möjligheter är välkommen att kontakta SEKs kansli för mer information.

SEK Svensk Elstandard

Box 1284
164 29 Kista
Tel 08-444 14 00
www.elstandard.se

English Version

**Semiconductor devices - Semiconductor interface for human
body communication - Part 2: Characterization of interfacing
performances
(IEC 62779-2:2016)**

Dispositifs à semiconducteurs - Interface à
semiconducteurs pour les communications via le corps
humain - Partie 2: Caractérisation des performances
d'interfaçage
(IEC 62779-2:2016)

Halbleiterbauelemente - Halbleiterschnittstelle zur
Kommunikation über den menschlichen Körper -
Teil 2: Beschreibung der Schnittstellenfunktion
(IEC 62779-2:2016)

This European Standard was approved by CENELEC on 2016-03-24. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

European foreword

The text of document 47/2268/FDIS, future edition 1 of IEC 62779-2, prepared by IEC/TC 47 "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62779-2:2016.

The following dates are fixed:

- latest date by which the document has to be implemented at (dop) 2016-12-24
national level by publication of an identical national
standard or by endorsement
- latest date by which the national standards conflicting with (dow) 2019-03-24
the document have to be withdrawn

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 62779-2:2016 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following note has to be added for the standard indicated :

IEC 62779	NOTE	Harmonized in EN 62779 series.
-----------	------	--------------------------------

CONTENTS

FOREWORD.....	3
INTRODUCTION.....	5
1 Scope.....	6
2 Normative references.....	6
3 Terms, definitions and letter symbols	6
3.1 General terms	6
3.2 Signal characteristics	9
3.3 Letter symbols	11
4 Measurement of electrical performances of electrode	11
4.1 Measurement setup.....	11
4.2 Measurement apparatus and signal specifications.....	12
4.2.1 Transmitter and receiver module	12
4.2.2 Synchronization module	13
4.2.3 Measurement equipment	13
4.2.4 Signal specifications	13
4.3 Measurement procedure.....	14
4.3.1 General	14
4.3.2 Attachment of transmitter and receiver modules.....	14
4.3.3 Transmission of pulse and synchronization signals	14
4.3.4 Synchronization of measurement equipment.....	14
4.3.5 Signal processing in receiver module.....	14
4.3.6 Measurement of pulse and processed signal.....	14
4.3.7 Compensation for signal processing	14
4.3.8 Computation of impulse response and complex transfer function.....	14
4.4 Post processing for electrode performances.....	14
4.4.1 General	14
4.4.2 In-band average signal-loss	14
4.4.3 In-band average phase-shift	15
4.4.4 RMS delay	15
4.4.5 Coherent bandwidth	15
Bibliography	17
Figure 1 – Pulse signal	8
Figure 2 – Synchronization signal.....	9
Figure 3 – Measurement setup.....	12
Table 1 – Letter symbols.....	11

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES – SEMICONDUCTOR INTERFACE
FOR HUMAN BODY COMMUNICATION –****Part 2: Characterization of interfacing performances**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as “IEC Publication(s)”). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 62779-2 has been prepared by IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47/2268/FDIS	47/2278/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62779 series, published under the general title *Semiconductor devices – Semiconductor interface for human body communication*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

INTRODUCTION

The IEC 62779 series is composed of three parts as follow:

- IEC 62779-1 defines general requirements of a semiconductor interface for human body communication. It includes general and functional specifications of the interface.
- IEC 62779-2 defines a measurement method on electrical performances of an electrode that constructs a semiconductor interface for human body communication.
- IEC 62779-3 defines functional type of a semiconductor interface for human body communication, and operational conditions of the interface.

SEMICONDUCTOR DEVICES – SEMICONDUCTOR INTERFACE FOR HUMAN BODY COMMUNICATION –

Part 2: Characterization of interfacing performances

1 Scope

This part of IEC 62779 defines a measurement method on electrical performances of an electrode that composes a semiconductor interface for human body communication (HBC). In the measurement method, a signal transmitter is electrically isolated from a signal receiver, so an isolation condition between the transmitter and receiver is maintained to accurately measure the electrode's performances. This part includes general and functional specifications of the measurement method.

HBC uses the body of a user as a transmission medium using near-field coupling inside the body: a signal transmitter and receiver are coupled with each other through a near field that is formed inside the human body and air. The intensity of the near field is strong especially inside the body due to high dielectric constant of the body, so a data signal is transmitted through the human body by modulating the near field. A signal transmitter and receiver for HBC include an internal ground respectively, and, in most HBC applications, the grounds are separated from each other as maintaining the coupling condition through the air. Quality of a data transmission strongly depends on a coupling degree between the grounds; hence, it is important to maintain the coupling degree between grounds of a signal transmitter and receiver for an accurate measurement of the electrode's performances. This part defines a measurement method to measure electrical performances of an electrode while the coupling degree between grounds of a signal transmitter and receiver is maintained.

NOTE 1 HBC semiconductor interface consists of an electrode and analog front end.

NOTE 2 General analog and digital modulation techniques can be used to modulate a near field used in HBC, and a modulation technique to be used is determined according to required performances for a data transmission and a HBC application.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

None.